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FDMS86101A

October 2014

N-Channel Shielded Gate PowerTrench® MOSFET 100 V, 60 A, 8 m Ω

Features

- Shielded Gate MOSFET Technology
- Max $r_{DS(on)} = 8 \text{ m}\Omega$ at $V_{GS} = 10 \text{ V}$, $I_D = 13 \text{ A}$
- Max $r_{DS(on)} = 13.5 \text{ m}\Omega$ at $V_{GS} = 6 \text{ V}$, $I_D = 9.5 \text{ A}$
- Advanced Package and Silicon combination for low r_{DS(on)} and high efficiency
- MSL1 robust package design
- 100% UIL tested
- 100% Rg tested
- RoHS Compliant

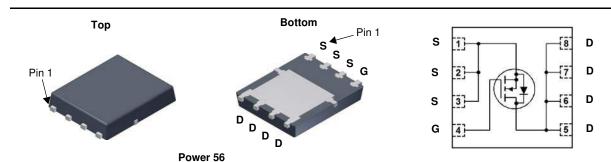


General Description

This N-Channel MOSFET is produced using Fairchild Semiconductor's advanced PowerTrench® process that incorporates Shielded Gate technology. This process has been optimized for the on-state resistance and yet maintain superior switching performance.

Application

■ DC-DC Conversion



MOSFET Maximum Ratings T_A = 25 °C unless otherwise noted

Symbol	Param	eter		Ratings	Units
V_{DS}	Drain to Source Voltage			100	V
V_{GS}	Gate to Source Voltage			±20	V
I _D	Drain Current -Continuous	T _C = 25 °C		60	
	-Continuous	T _A = 25 °C	(Note 1a)	13	Α
	-Pulsed			180	
E _{AS}	Single Pulse Avalanche Energy		(Note 3)	486	mJ
P _D	Power Dissipation	T _C = 25 °C		104	w
	Power Dissipation	T _A = 25 °C	(Note 1a)	2.5	VV
T _J , T _{STG}	Operating and Storage Junction Tempera	ature Range		-55 to +150	°C

Thermal Characteristics

$R_{\theta JC}$	Thermal Resistance, Junction to Case		1.2	°C/W
$R_{\theta,JA}$	Thermal Resistance, Junction to Ambient	(Note 1a)	50	C/VV

Package Marking and Ordering Information

Device Marking	Device	Package	Reel Size	Tape Width	Quantity
FDMS86101A	FDMS86101A	Power 56	13 "	12 mm	3000 units

Electrical Characteristics T_J = 25 °C unless otherwise noted

Symbol	Parameter	Test Conditions	Min	Тур	Max	Units
Off Chara	cteristics					
BV_{DSS}	Drain to Source Breakdown Voltage	$I_D = 250 \mu A, V_{GS} = 0 V$	100			V
$\frac{\Delta BV_{DSS}}{\Delta T_{J}}$	Breakdown Voltage Temperature Coefficient	I_D = 250 μ A, referenced to 25 °C		71		mV/°C
I _{DSS}	Zero Gate Voltage Drain Current	V _{DS} = 80 V, V _{GS} = 0 V			800	nA
I _{GSS}	Gate to Source Leakage Current	$V_{GS} = \pm 20 \text{ V}, V_{DS} = 0 \text{ V}$			±100	nA

On Characteristics

$V_{GS(th)}$	Gate to Source Threshold Voltage	$V_{GS} = V_{DS}, I_D = 250 \mu A$	2.0	3.1	4.0	V
$\frac{\Delta V_{GS(th)}}{\Delta T_J}$	Gate to Source Threshold Voltage Temperature Coefficient	$I_D = 250 \mu A$, referenced to 25 °C		-9		mV/°C
		V _{GS} = 10 V, I _D = 13 A		6.3	8	
r _{DS(on)}	Static Drain to Source On Resistance	$V_{GS} = 6 \text{ V}, I_D = 9.5 \text{ A}$		8.0	13.5	mΩ
		$V_{GS} = 10 \text{ V}, I_D = 13 \text{ A}, T_J = 125 \text{ °C}$		10.3	13.1	
g _{FS}	Forward Transconductance	V _{DS} = 10 V, I _D = 13 A		53		S

Dynamic Characteristics

C _{iss}	Input Capacitance	V 50.V.V 0.V		3095	4120	pF
C _{oss}	Output Capacitance	$V_{DS} = 50 \text{ V}, V_{GS} = 0 \text{ V},$ $f = 1 \text{ MHz}$		460	615	pF
C _{rss}	Reverse Transfer Capacitance	1 - 1 1011 12		15	25	pF
R_a	Gate Resistance		0.1	1.6	3.3	Ω

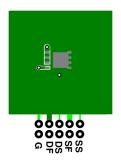
Switching Characteristics

t _{d(on)}	Turn-On Delay Time			19	35	ns
t _r	Rise Time	$V_{DD} = 50 \text{ V}, I_{D} = 13 \text{ A},$		5.4	11	ns
t _{d(off)}	Turn-Off Delay Time	$V_{GS} = 10 \text{ V}, R_{GEN} = 6 \Omega$		27	44	ns
t _f	Fall Time			4	10	ns
Q_g	Total Gate Charge	V _{GS} = 0 V to 10 V		42	58	nC
Qg	Total Gate Charge	$V_{GS} = 0 \text{ V to 5 V} V_{DD} = 50 \text{ V}$,	22	31	nC
Q _{gs}	Gate to Source Charge	I _D = 13 A		13.5		nC
Q_{gd}	Gate to Drain "Miller" Charge			6.2		nC

Drain-Source Diode Characteristics

V	Source to Drain Diode Forward Voltage	$V_{GS} = 0 \text{ V}, I_S = 2.1 \text{ A}$ (Note 2)	0.74	1.2	V
V_{SD}	Source to Drain Diode Forward Voltage	V _{GS} = 0 V, I _S = 13 A (Note 2)	0.81	1.3	V
t _{rr}	Reverse Recovery Time		64	102	ns
Q _{rr}	Reverse Recovery Charge		102	164	nC

Notes:
1. R_{0JA} is determined with the device mounted on a 1 in² pad 2 oz copper pad on a 1.5 x 1.5 in. board of FR-4 material. R_{0JC} is guaranteed by design while R_{0CA} is determined by the user's board design.



a. 50 °C/W when mounted on a 1 in² pad of 2 oz copper.



b. 125 °C/W when mounted on a minimum pad of 2 oz copper.

^{2.} Pulse Test: Pulse Width < 300 μ s, Duty cycle < 2.0%.

^{3.} E_{AS} 486 mJ is based on starting T_{J} = 25 °C, L = 3 mH, I_{AS} = 18 A, V_{DD} = 100 V, V_{GS} = 10 V. 100% test at L = 0.1 mH, I_{AS} = 51 A.

Typical Characteristics T_{.1} = 25 °C unless otherwise noted

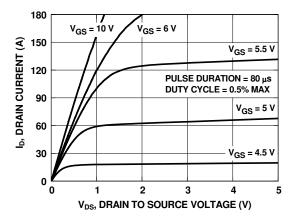


Figure 1. On-Region Characteristics

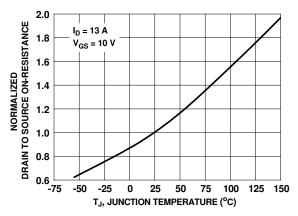


Figure 3. Normalized On-Resistance vs Junction Temperature

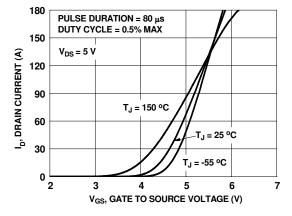


Figure 5. Transfer Characteristics

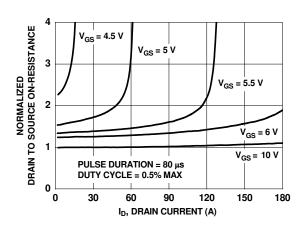


Figure 2. Normalized On-Resistance vs Drain Current and Gate Voltage

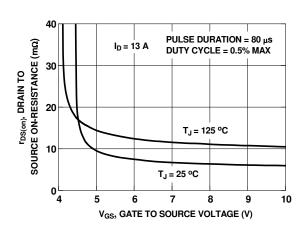


Figure 4. On-Resistance vs Gate to Source Voltage

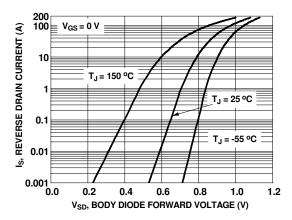


Figure 6. Source to Drain Diode Forward Voltage vs Source Current

Typical Characteristics $T_J = 25$ °C unless otherwise noted

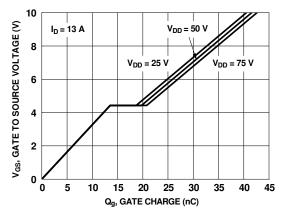


Figure 7. Gate Charge Characteristics

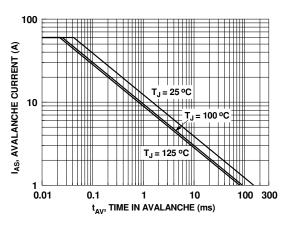


Figure 9. Unclamped Inductive Switching Capability

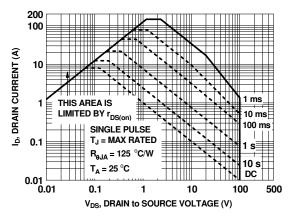


Figure 11. Forward Bias Safe Operating Area

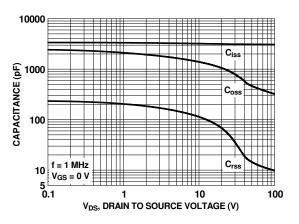


Figure 8. Capacitance vs Drain to Source Voltage

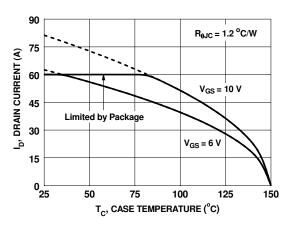


Figure 10. Maximum Continuous Drain Current vs Case Temperature

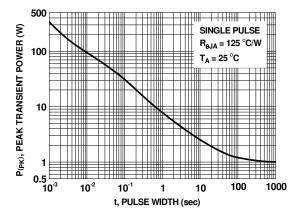


Figure 12. Single Pulse Maximum Power Dissipation

Typical Characteristics T_J = 25 °C unless otherwise noted

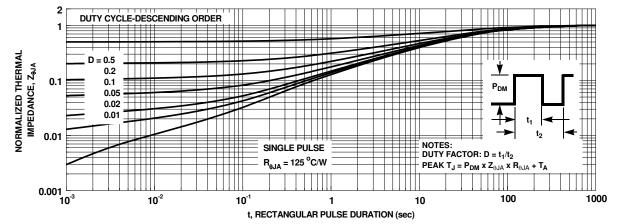
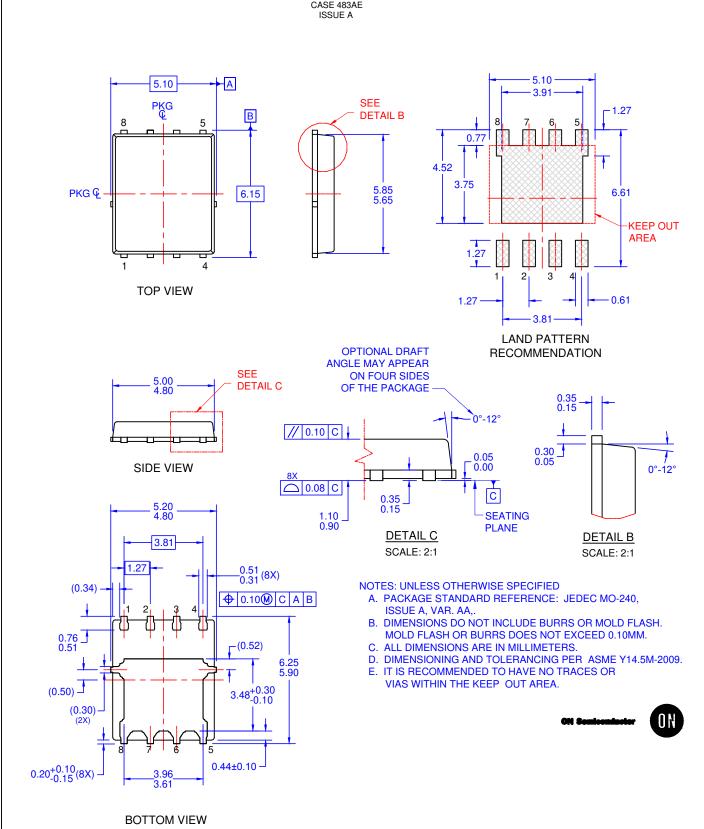


Figure 13. Junction-to-Ambient Transient Thermal Response Curve



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